

Remarks/Arguments

Claim Summary

By this Amendment, claims 1 and 9 have been revised, and new claims 14 and 15 have been added for the Examiner's consideration.

Claims 1-15 are now pending in the application.

Allowable Claims

Applicants acknowledge with thanks the indicated allowance of claims 2-5 and 10-13.

35 U.S.C. ¶102

Claims 1 and 6-9 were rejected under 35 U.S.C. ¶102 as being unpatentable over Kizer et al. (U.S. Pub. No. 2004/0075462). Applicants respectfully traverse this rejection with respect to the now-pending claims 1, 6-9 and 14-15.

The invention of claims 1, 6-9 and 14-15 is characterized by the detection of a process variation which affects an operating characteristic of MOS transistors of the semiconductor device. For example, process variations can alter the sizes of the MOS transistors, which in turn can vary the turn-on resistances of the transistors. Please see, e.g., paragraph [0053] of the present specification.

Applicants can find no teaching or suggestion in Kizer et al. of detecting a process variation as recited in claims 1, 6-9 and 14-15. Rather, Kizer et al. is primarily directed to the use of a digital error accumulator in the feedback path of clock circuit. See, e.g., paragraph [0031] of Kizer et al.


For at least the reasons stated above, Applicants respectfully contend that claims 1, 6-9 and 14-15 are not anticipated by Kizer et al.

Conclusion

No other issues remaining, reconsideration and favorable action upon the claims 1-15 now pending in the application are requested.

Respectfully submitted,

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October 16, 2006

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